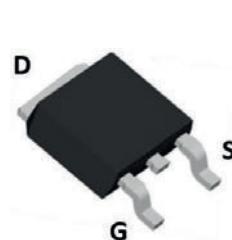
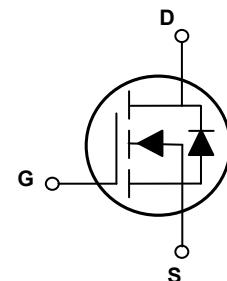


Main Product Characteristics

$V_{(BR)DSS}$	150V
$R_{DS(ON)}$	14mΩ (Max.)
I_D	100A



TO-252 (DPAK)



Schematic Diagram



Features and Benefits

- Grand Turbo MOSFET process technology.
- Optimized the cell structure.
- Low on-resistance with low gate charge.
- Featuring low switching and drive losses.
- Fast switching and reverse body recovery.
- High ruggedness and robustness.

Description

The GSFD14015 utilizes the latest techniques to achieve high cell density and low on-resistance. These features make this device extremely efficient and reliable for use in high efficiency switch mode power supplies and a wide variety of other applications.

Absolute Maximum Ratings ($T_J=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Max.	Unit
Drain-Source Voltage	$V_{(BR)DSS}$	150	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous ($T_C=25^\circ\text{C}$) @ Steady-State	I_D	100	A
Drain Current-Continuous ($T_C=100^\circ\text{C}$) @ Steady-State		63	
Pulsed Drain Current ²	I_{DM}	400	A
Single Pulse Avalanche Energy ¹	E_{AS}	162	mJ
Single Pulsed Avalanche Current	I_{AS}	57	A
Power Dissipation ($T_C=25^\circ\text{C}$) ³	P_D	100	W
		0.8	W/ $^\circ\text{C}$
Junction-to-Ambient (PCB Mounted, Steady-State)	$R_{\theta JA}$	50	$^\circ\text{C}/\text{W}$
Junction to Case	$R_{\theta JC}$	1.25	$^\circ\text{C}/\text{W}$
Operating Junction Temperature Range	T_J	-55 to +150	$^\circ\text{C}$
Storage Temperature Range	T_{STG}	-55 to +150	$^\circ\text{C}$
Soldering Temperature	T_{SOLD}	260	$^\circ\text{C}$

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
On / Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=250\mu\text{A}$	150	-	-	V
Drain-Source Leakage Current	$\text{I}_{\text{DS}(\text{S})}$	$\text{V}_{\text{DS}}=150\text{V}, \text{V}_{\text{GS}}=0\text{V}, \text{T}_J=25^\circ\text{C}$	-	-	1	μA
		$\text{V}_{\text{DS}}=150\text{V}, \text{V}_{\text{GS}}=0\text{V}, \text{T}_J=125^\circ\text{C}$	-	5	-	μA
Gate-Source Forward Leakage	I_{GSS}	$\text{V}_{\text{GS}}=\pm20\text{V}, \text{V}_{\text{DS}}=0\text{V}$	-	-	±100	nA
Static Drain-Source On-Resistance	$\text{R}_{\text{DS}(\text{ON})}$	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=50\text{A}$	-	12.5	14	$\text{m}\Omega$
Gate Resistance	R_g	$f=1\text{MHz}$	-	1.6	-	Ω
Gate Threshold Voltage	$\text{V}_{\text{GS}(\text{TH})}$	$\text{V}_{\text{GS}}=\text{V}_{\text{DS}}, \text{I}_D=250\mu\text{A}$	2	-	2.4	V
Dynamic and Switching Characteristics						
Total Gate Charge ^{4,5}	Q_g	$\text{V}_{\text{DD}}=75\text{V}, \text{I}_D=50\text{A}, \text{V}_{\text{GS}}=10\text{V}$	-	36	-	nC
Gate-Source Charge ^{4,5}	Q_{gs}		-	24	-	
Gate-to-Drain("Miller") Charge ^{4,5}	Q_{gd}		-	4.8	-	
Gate Plateau ^{4,5}	$\text{V}_{\text{plateau}}$		-	8	-	
Turn-On Delay Time ^{4,5}	$t_{\text{d}(\text{on})}$	$\text{V}_{\text{DD}}=75\text{V}, \text{R}_g=1.6\Omega, \text{V}_{\text{GS}}=10\text{V}, \text{I}_D=50\text{A}$	-	22	-	nS
Rise Time ^{4,5}	t_r		-	25	-	
Turn-Off Delay Time ^{4,5}	$t_{\text{d}(\text{off})}$		-	25	-	
Fall Time ^{4,5}	t_f		-	11	-	
Input Capacitance	C_{iss}	$\text{V}_{\text{DS}}=75\text{V}, \text{V}_{\text{GS}}=0\text{V}, f=1\text{MHz}$	-	2614	-	pF
Output Capacitance	C_{oss}		-	328	-	
Reverse Transfer Capacitance	C_{rss}		-	15	-	
Drain-Source Diode Characteristics and Maximum Ratings						
Continuous Source Current (Body Diode)	I_s	MOSFET symbol showing the integral reverse p-n junction diode.	-	-	100	A
Diode Pulse Current	$\text{I}_{\text{s,pulse}}$	-	-	400	A	
Diode Forward Voltage	V_{SD}	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_s=50\text{A}$	-	-	1.4	V
Reverse Recovery Time ⁴	t_{rr}	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_s=50\text{A}, \frac{d\text{I}_s}{dt}=100\text{A}/\mu\text{s}, \text{V}_R=48\text{V}$	-	96	-	nS
Reverse Recovery Charge ⁴	Q_{rr}		-	0.35	-	nC

Notes:

1. EAS test condition: $L=0.1\text{mH}, \text{V}_{\text{DD}}=100\text{V}, \text{R}_g=25\Omega$.
2. Pulse time of $5\mu\text{s}$.
3. The dissipated power value will change with the temperature. When it is greater than 25°C , the dissipated power value will decrease by $1.11^\circ\text{C}/\text{W}$ for every 1 degree of temperature increase.
4. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$
5. Basically unaffected by operating temperature.

Typical Electrical and Thermal Characteristic Curves

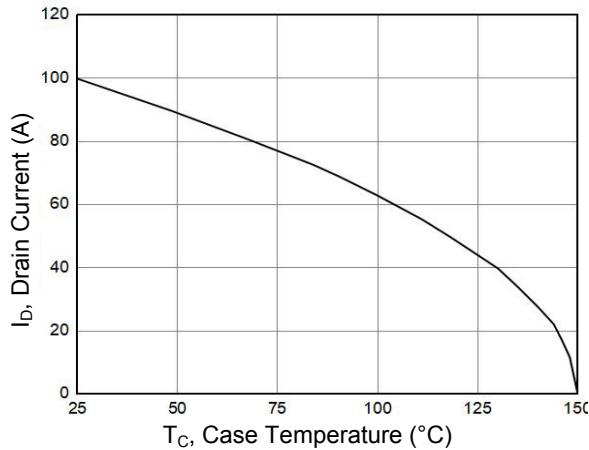
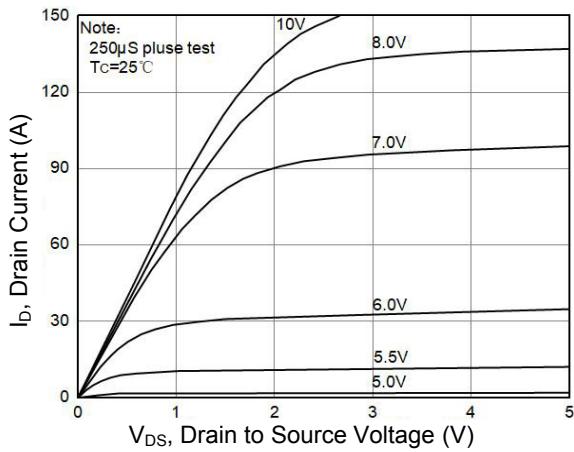


Figure 1. Typical Output Characteristics

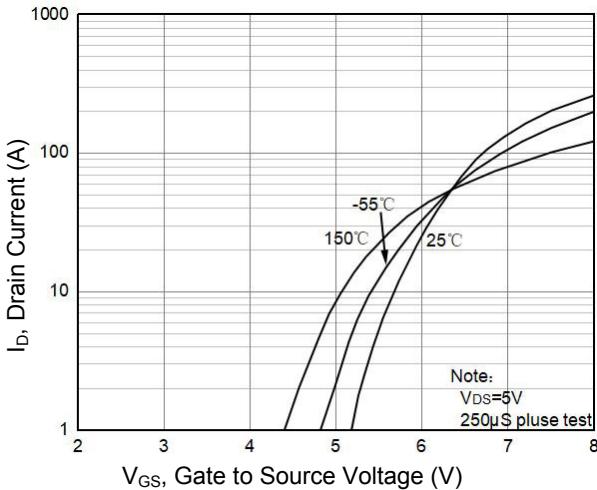


Figure 2. Power Dissipation vs. T_c

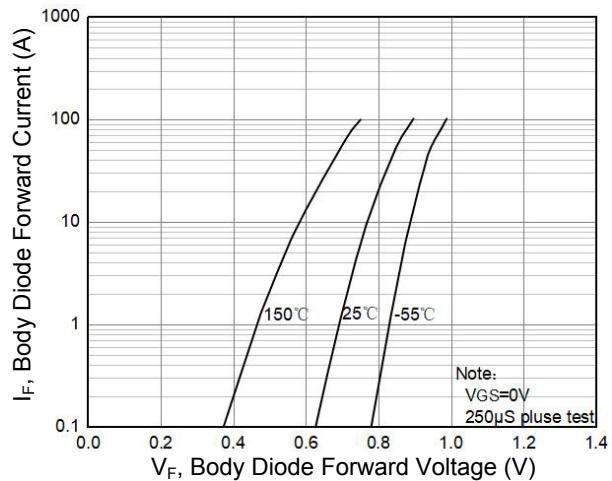


Figure 3. Transfer Characteristics

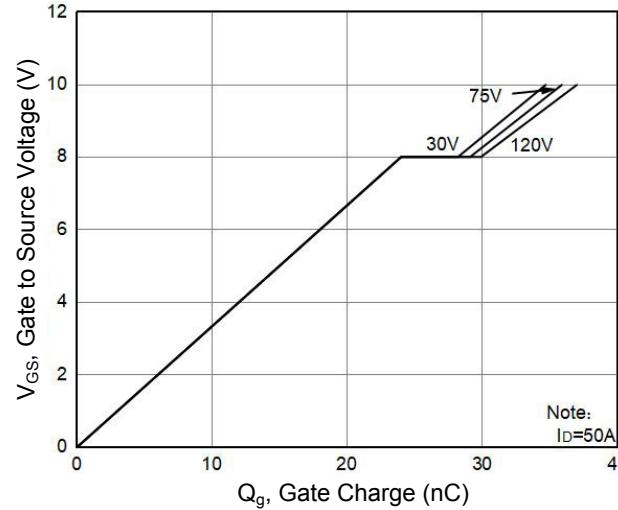
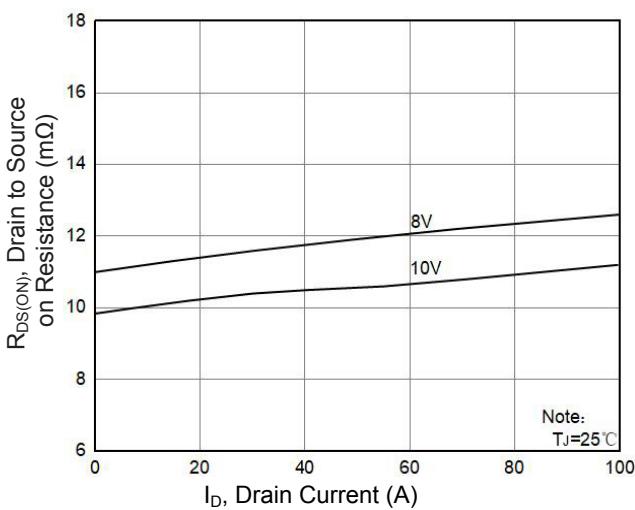


Figure 5. $R_{DS(\text{ON})}$ vs. Drain Current

Figure 6. Gate Charge Characteristics

Typical Electrical and Thermal Characteristic Curves

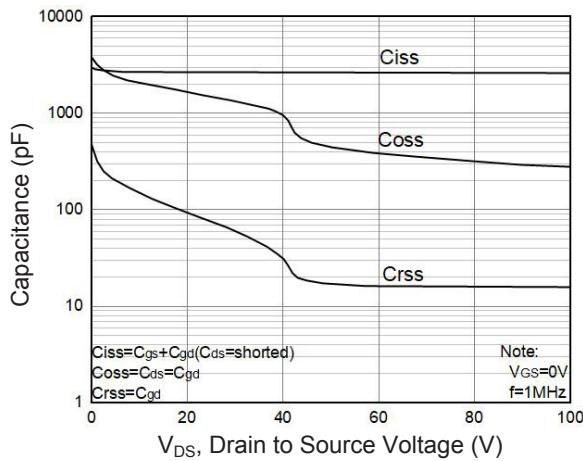


Figure 7. Capacitance Characteristics

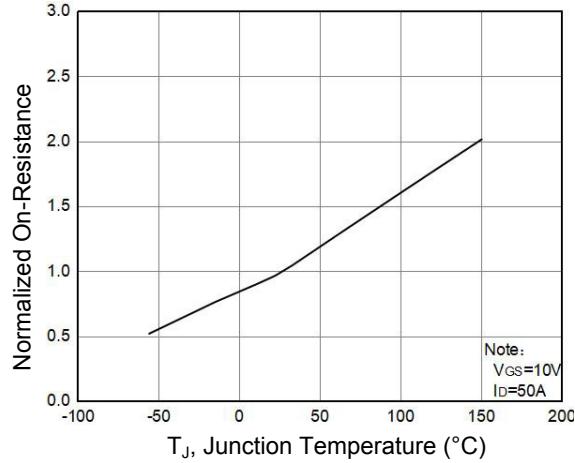


Figure 8. Normalized $R_{DS(ON)}$ vs. T_J

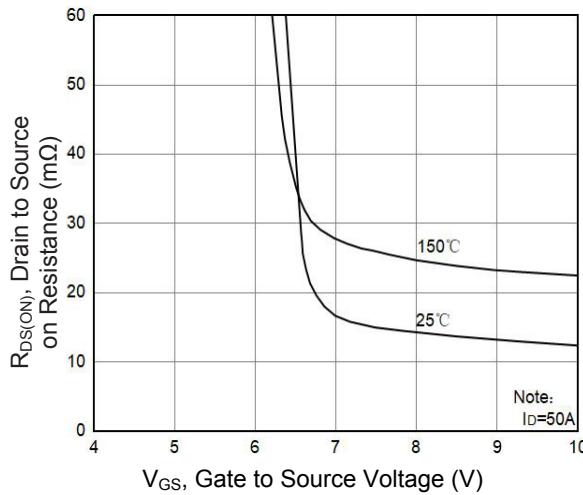


Figure 9. $R_{DS(ON)}$ vs. V_{GS}

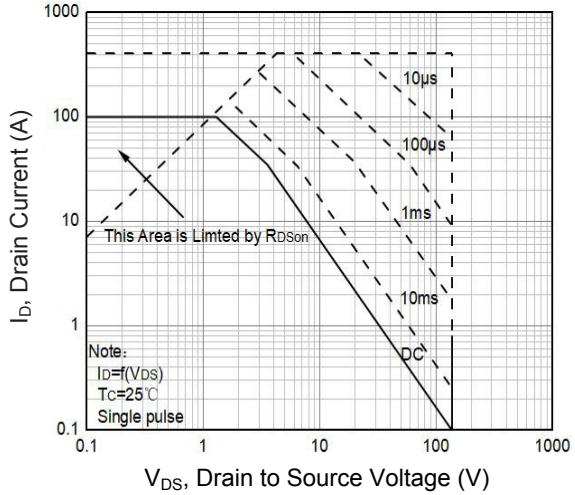


Figure 10. Safe Operation Area

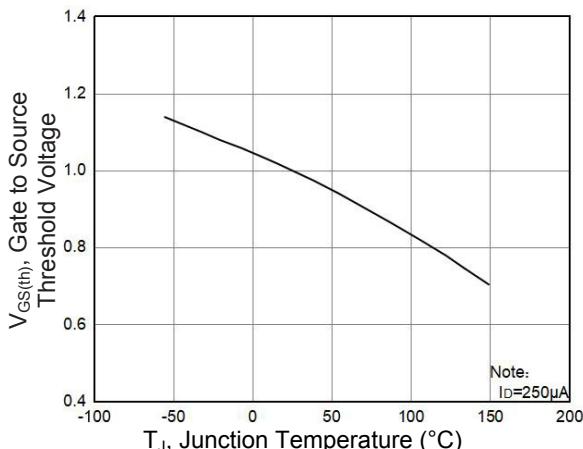


Figure 11. Gate Threshold Voltage vs T_J

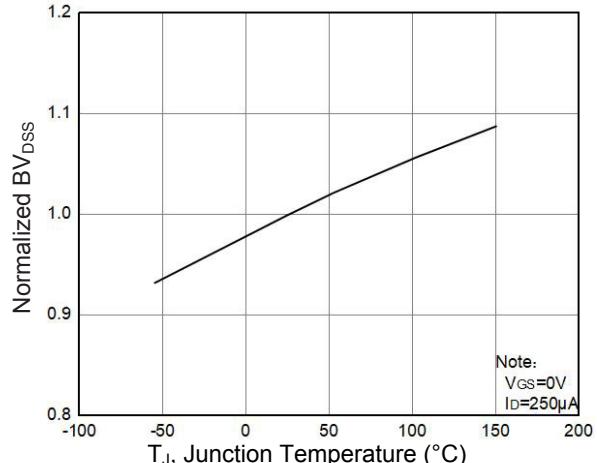
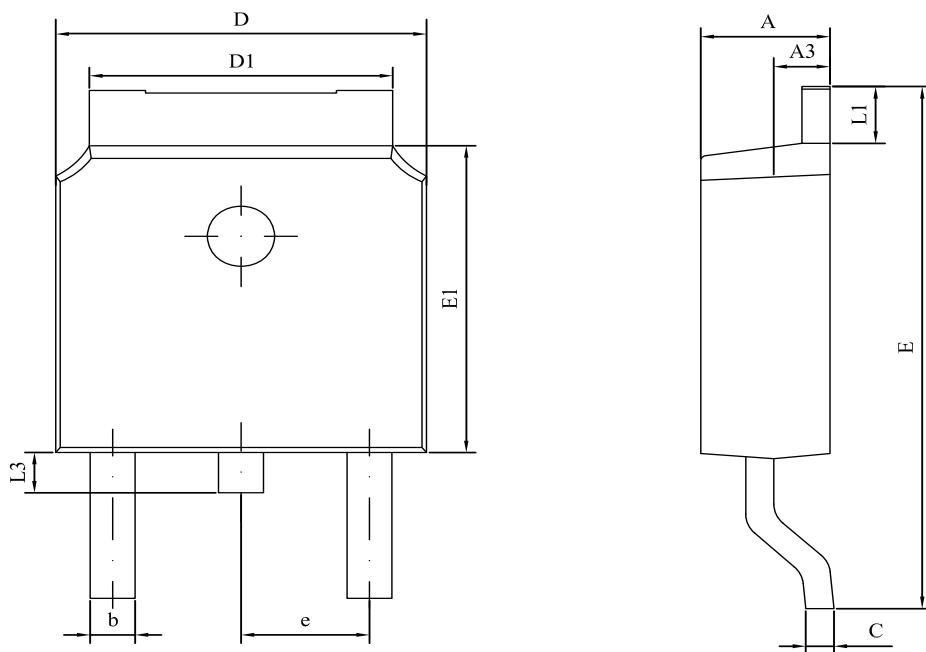


Figure 12. Normalized BV_{DSS} vs. T_J

Package Outline Dimensions TO-252(DPAK)



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	2.150	2.400	0.085	0.094
A3	0.900	1.100	0.035	0.043
b	0.500	0.900	0.020	0.035
C	0.400	0.650	0.016	0.026
D	6.300	6.900	0.248	0.272
D1	4.950	5.500	0.195	0.217
E	9.400	10.410	0.370	0.410
E1	5.900	6.300	0.232	0.248
e	2.286 BSC		0.090 BSC	
L1	0.890	1.270	0.035	0.050
L3	0.600	1.100	0.024	0.043

Order Information

Device	Package	Marking	Carrier	Quantity
GSFD14015	TO-252(DPAK)	D14015	Tape & Reel	2,500 Pcs / Reel

For more information, please contact us at: inquiry@goodarksemi.com